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(54) Title: METHOD OF TRANSMISSION ELECTRON MICROSCOPE FOIL PREPARATION USING LASER

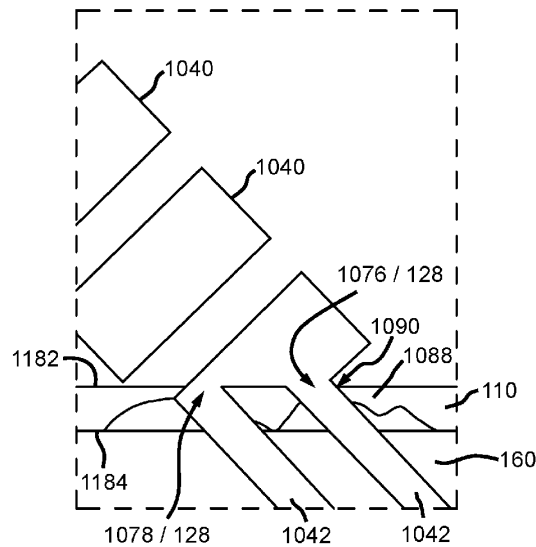


FIG. 5B

(57) Abstract: A sample for TEM analysis and a method of preparing the sample. The method includes thinning a specimen to a bulk thickness that is non-transparent to electrons by laser milling and laser ablating a region such that the region is thinner than the bulk thickness. The ablating is stopped in response to sensing that at least one penetrated part of the region is transparent to electrons, such that a sampling point for the TEM analysis is selectable from an ablated area neighboring the at least one penetrated part.

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